

### N-CHANNEL MOS FIELD EFFECT TRANSISTOR FOR SWITCHING

#### DESCRIPTION

This product is a switching device which can be driven directly by a 4.5-V power source.

The  $\mu$ PA1803 features a low on-state resistance and excellent switching characteristics, and is suitable for applications such as power switch of portable machine and so on.

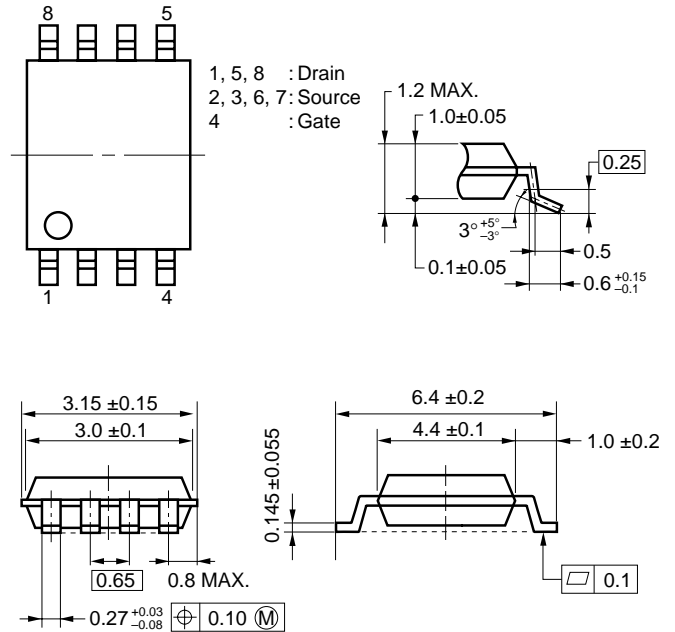
#### FEATURES

- Can be driven by a 4.5-V power source
- Low on-state resistance  
 $R_{DS(on)1} = 12 \text{ m}\Omega \text{ MAX. (} V_{GS} = 10 \text{ V, } I_D = 4.0 \text{ A)}$   
 $R_{DS(on)2} = 16 \text{ m}\Omega \text{ MAX. (} V_{GS} = 4.5 \text{ V, } I_D = 4.0 \text{ A)}$
- Built-in G-S protection diode against ESD

#### ORDERING INFORMATION

PART NUMBER	PACKAGE
$\mu$ PA1803GR-9JG	Power TSSOP8

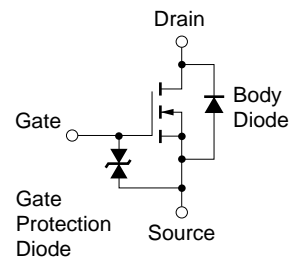
#### PACKAGE DRAWING (Unit : mm)



#### ABSOLUTE MAXIMUM RATINGS ( $T_A = 25^\circ\text{C}$ )

Drain to Source Voltage	$V_{DSS}$	30	V
Gate to Source Voltage	$V_{GSS}$	$\pm 20$	V
Drain Current (DC)	$I_{D(DC)}$	$\pm 8.0$	A
Drain Current (pulse) <sup>Note1</sup>	$I_{D(pulse)}$	$\pm 32$	A
Total Power Dissipation <sup>Note2</sup>	$P_T$	2.0	W
Channel Temperature	$T_{ch}$	150	$^\circ\text{C}$
Storage Temperature	$T_{stg}$	-55 to +150	$^\circ\text{C}$

#### EQUIVALENT CIRCUIT



- Notes 1.**  $PW \leq 10 \mu\text{s}$ , Duty Cycle  $\leq 1\%$
- 2.** Mounted on ceramic substrate of  $5000 \text{ mm}^2 \times 1.1 \text{ mm}$

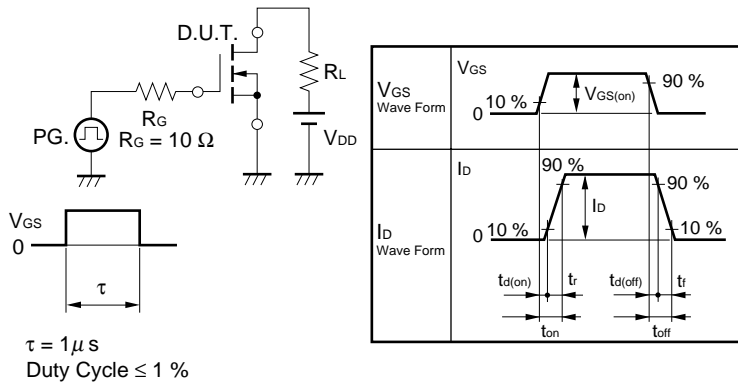
**Remark** The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

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 Not all devices/types available in every country. Please check with local NEC representative for availability and additional information.

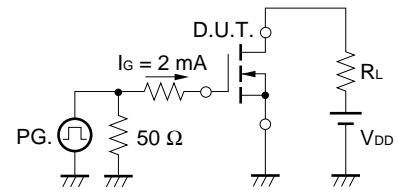
**ELECTRICAL CHARACTERISTICS (T<sub>A</sub> = 25 °C)**

CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 30 V, V <sub>GS</sub> = 0 V			10	μA
Gate Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> = ±20 V, V <sub>DS</sub> = 0 V			±10	μA
Gate to Source Cut-off Voltage	V <sub>GS(off)</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	1.0	1.9	2.5	V
Forward Transfer Admittance	y <sub>fs</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 4.0 A	3	14		S
Drain to Source On-state Resistance	R <sub>DS(on)1</sub>	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 4.0 A		8.6	12	mΩ
	R <sub>DS(on)2</sub>	V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 4.0 A		11	16	mΩ
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> = 10 V		1880		pF
Output Capacitance	C <sub>oss</sub>	V <sub>GS</sub> = 0 V		571		pF
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1 MHz		214		pF
Turn-on Delay Time	t <sub>d(on)</sub>	V <sub>DD</sub> = 15 V		27		ns
Rise Time	t <sub>r</sub>	I <sub>D</sub> = 4.0 A		77		ns
Turn-off Delay Time	t <sub>d(off)</sub>	V <sub>GS(on)</sub> = 10 V		72		ns
Fall Time	t <sub>f</sub>	R <sub>G</sub> = 10 Ω		47		ns
Total Gate Charge	Q <sub>G</sub>	V <sub>DS</sub> = 24 V		36		nC
Gate to Source Charge	Q <sub>GS</sub>	I <sub>D</sub> = 8.0 A		5.1		nC
Gate to Drain Charge	Q <sub>GD</sub>	V <sub>GS</sub> = 10 V		8.7		nC
Diode Forward Voltage	V <sub>F(S-D)</sub>	I <sub>F</sub> = 8.0 A, V <sub>GS</sub> = 0 V		0.78		V
Reverse Recovery Time	t <sub>rr</sub>	I <sub>F</sub> = 8.0 A, V <sub>GS</sub> = 0 V		37		ns
Reverse Recovery Charge	Q <sub>rr</sub>	di/dt = 100 A/μs		35		nC

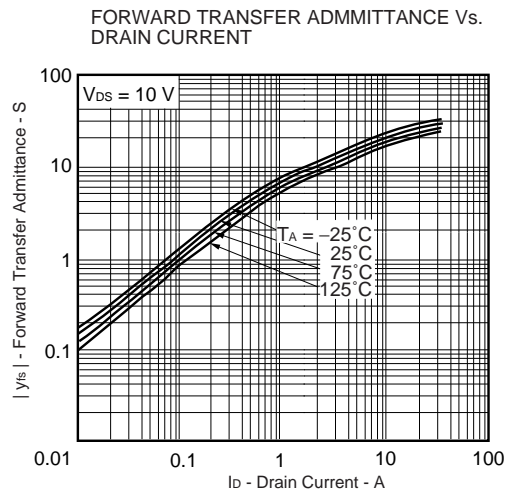
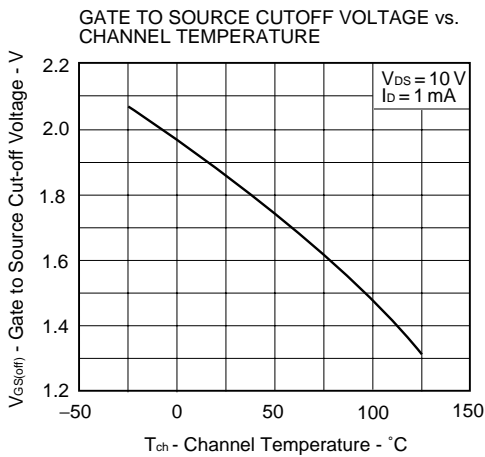
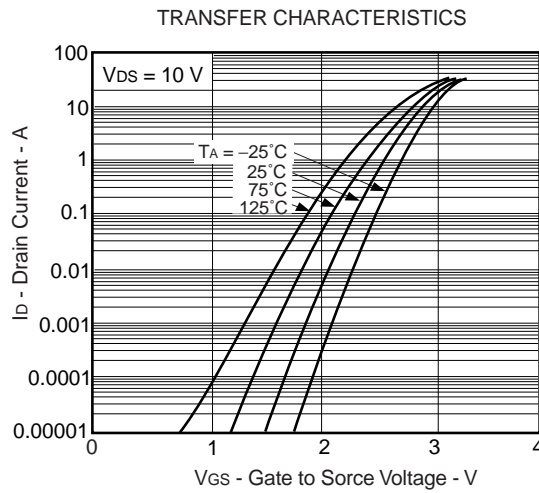
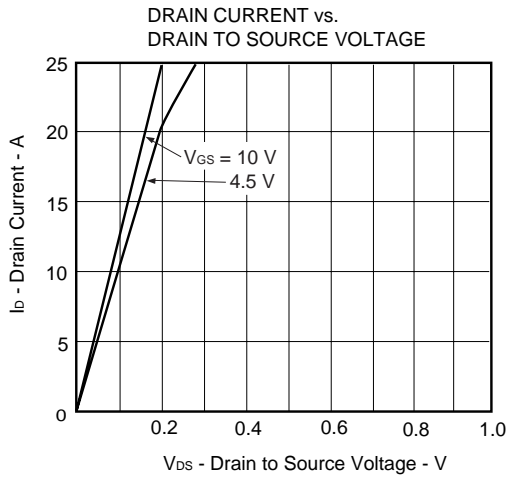
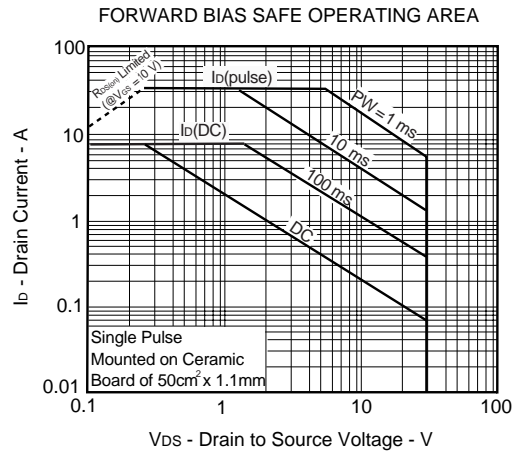
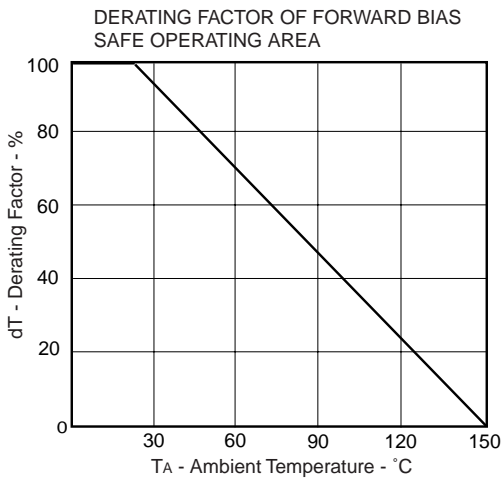
**TEST CIRCUIT 1 SWITCHING TIME**

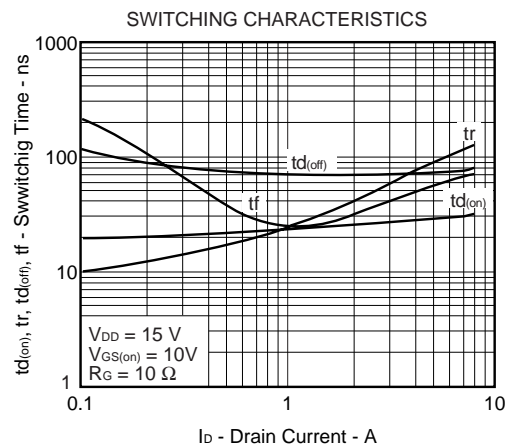
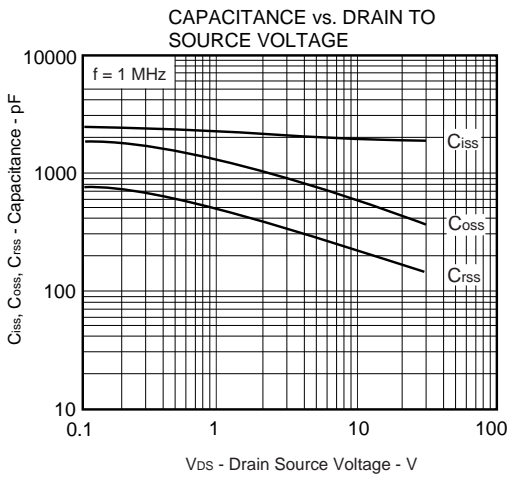
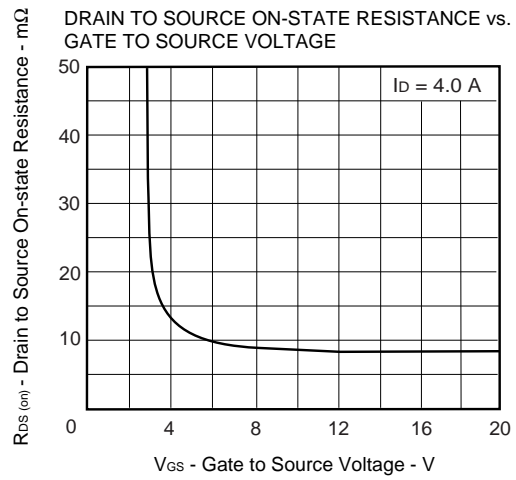
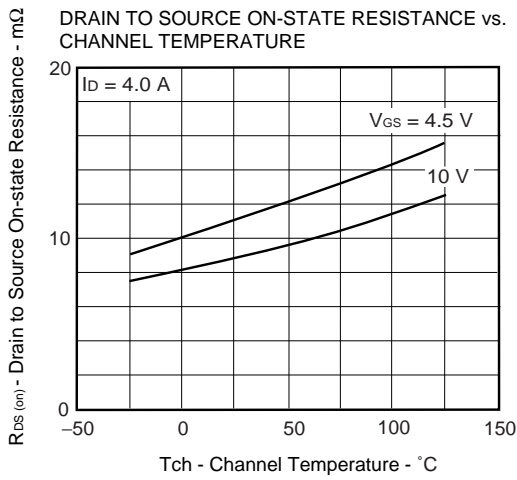
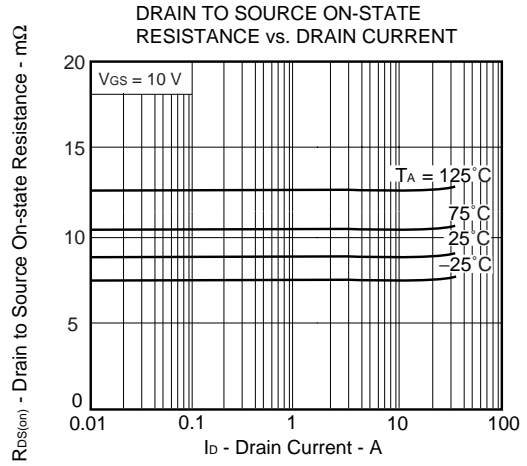
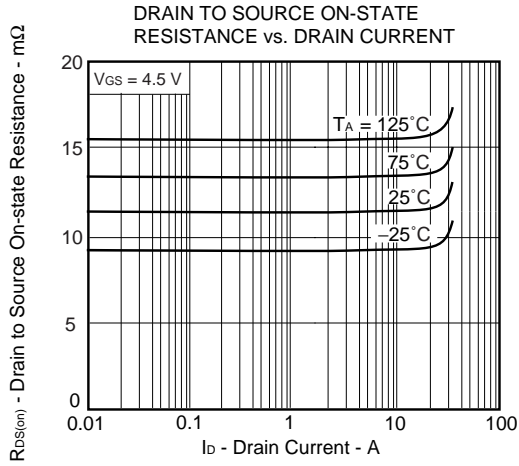


**TEST CIRCUIT 2 GATE CHARGE**

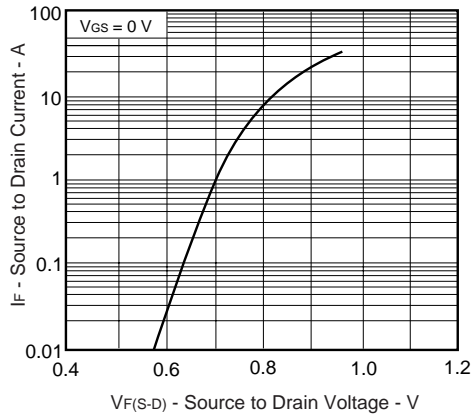


★ TYPICAL CHARACTERISTICS (T<sub>A</sub> = 25 °C)

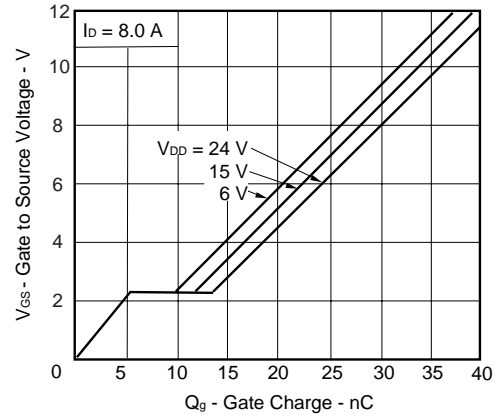




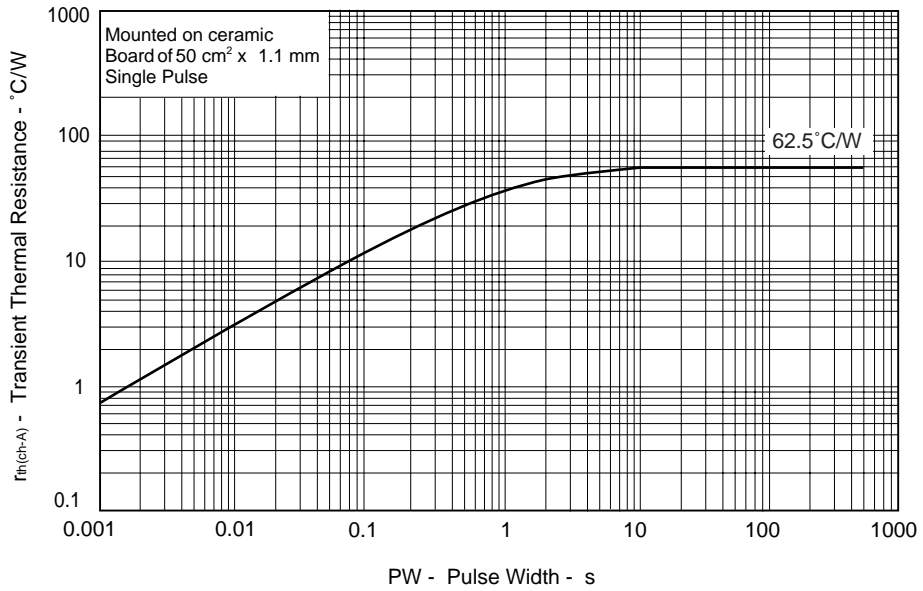
SOURCE TO DRAIN DIODE FORWARD VOLTAGE



DYNAMIC INPUT CHARACTERISTICS



TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH



[MEMO]

[MEMO]

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